TOSHIBA PHOTOCOUPLER

TLP181(V4)

 $\underline{\text{ATTACHMENT}}: \text{SPECIFICATIONS FOR } \underline{\text{VDE0884}} \text{ OPTION}$

Types: TLP181

Type designations for 'Option: (V4)', which are tested under VDE0884 requirements.

Ex. : TLP181 (V4-GR-TPR) V4 : VDE0884 option

GR: CTR rank name

TPR : standard taping name

Note : Use Toshiba standard type number for safety standard application.

Ex. TLP181 (V4-GR-TPR) → TLP181

VDE0884 ISOLATION CHARACTERISTICS

DESCRIPTION	SYMBOL	RATING	UNIT
Application Classification (DIN VDE0110 Teil 1/01.89, Table 1) for rated mains voltage≤150 V _{RMS} for rated mains voltage≤300 V _{RMS}		I-IV I-III	_
Climatic Classification (DIN IEC68 Teil 1/09.80)		55 / 100 / 21	_
Pollution Degree (DIN VDE0110 Teil 1/01.89)		2	_
Maximum Operating Insulation Voltage	U _{IORM}	565	Vpk
Input to output Test Voltage, Method A Upr=1.5×V _{IORM} , Type and Sample Test t _p =60sec, Partial Discharge<5pC	Upr	850	Vpk
Input to output Test Voltage, Method B Upr=1.875×V _{IORM} , 100% Production Test t _p =1sec, Partial Discharge<5pC	Upr	1060	Vpk
Highest Permissible Overvoltage (Transient Overvoltage, t _{pr} =10s)	U_{TR}	6000	Vpk
Safety Limiting Values (Max. permissible ratings in case of fault, also refer to thermal derating curve	т.	250	mA
Current (Input current If, Ps=0) Power (Output or Total Power Dissipation)	$egin{array}{ccc} ext{I}_{ ext{si}} \ ext{P}_{ ext{si}} \end{array}$	400	mW
Temperature	T_{si}	150	°C
Insulation Resistance, $V_{IO}\!=\!500V$, $Ta\!=\!25^{\circ}C$ $V_{IO}\!=\!500V$, $Ta\!=\!100^{\circ}C$ $V_{IO}\!=\!500V$, $Ta\!=\!Ts$	$ m R_{si}$		Ω

INSULATION RELATED SPECIFICATIONS

Minimum Creepage Distance *	Cr	4.0 mm	
Minimum Clearance *	Cl	4.0 mm	
Minimum Insulation Thickness	ti	0.4 mm	
Comperative Tracking Index (DIN IEC112/VDE0303, Part 1)	CTI	175 (VDE0110 Teil 1/01.89 Group Ⅱa)	

- * in accordance with DIN VDE0110 Teil 1/01.89, Table 2, & 4)
- 1. If a printed circuit is incorporated, the creepage distance and clearance may be reduced below this value. If this is not permissible, the user shall take suitable measures.
- 2. This photocoupler is suitable for 'safe electrical isolation' only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits. (Dieses Koppelelement ist fur "Sichere Elektrische Trennung" nur innerhalb der Sicherheitsgrenzdaten geeignet. Die Einhaltung der Sicherheitsgrenzen mu β durch Schutzschaltungen sichergestellt sein.)

TLP181

VDE Test sign : Marking on product

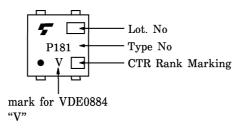
for VDE0884

Marking on paking

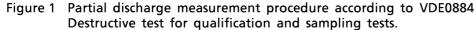
for VDE0884



Marking Example:



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Method A

(for type and sampling tests, destructive tests)

$$\begin{array}{lll} t_1,\ t_2 & =1\ to\ 10s \\ t_3,\ t_4 & =1s \\ t_P \ (\text{Measuring time for partial discharge}) = 50s \\ t_b & =62s \\ t_{ini} & =10s \end{array}$$

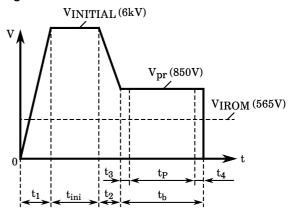
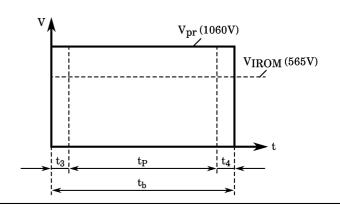


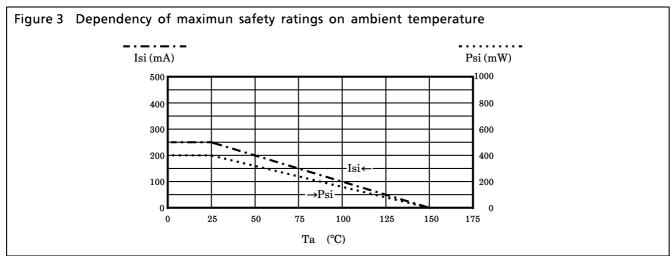
Figure 2 Partial discharge measurement procedure according to VDE0884 Non-desturctive test for 100% inspection.

Method B

(for sample test, non-destructive test)

 $\begin{array}{l} t_3,\,t_4 & = 0.1s \\ t_P\,(Measuring~time~for~partial~discharge) = 1s \\ t_h & = 1.2s \end{array}$





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000707EBC

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